



Image AF/2829

GR 00 P 1679

BOX AF

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450:

By: 

Date: February 25, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No. : 09/826,594 Confirmation No. 4825
Applicant : Dieter Kantz et al.
Filed : April 5, 2001
TC/A.U. : 2829
Examiner : Ernest F. Karlsen
Title : Test Configuration for the Functional Testing
of a Semiconductor Chip

Docket No. : GR 00 P 1679
Customer No. : 24131

BOX AF

Hon. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT under 37 C.F.R. § 1.116

S i r :

In response to the final Office action dated December 2, 2003,
please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of
claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 5 of this paper.